

# Test Report

**Customer:**

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## RF test report

180371-AU01+W01



**DESKO GmbH**

**Keyboard with multiple card readers**

NEPTUN chrom



The test result refers exclusively to the tested model.  
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## Accreditation:



Registration number (FCC): 997268  
Test Firm Type "accredited": Valid until 2019-05-06  
MRA US-EU, FCC designation number: DE0010  
BnetzA-CAB-02/21-02/04 Valid until 2018-11-27

## Test Laboratory:

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# 1 Test regulations

47 CFR Part 2: 10-2017	Code of Federal Regulations Part 2 (Frequency allocation and radio treaty matters; General rules and regulations) of the Federal Communication Commission (FCC)
47 CFR Part 15: 03-2017	Code of Federal Regulations Part 15 (Radio Frequency Devices) of the Federal Communication Commission (FCC)
ANSI C63.10:2013-06	American National Standard of Procedures for Compliance Testing of Unlicensed Wireless Devices
FCC KDB 174176 D01 June 3, 2015	AC power-line conducted emissions Frequently Asked Questions



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## 2 Summary of test results

Standard

Test result

47 CFR Part 15,  
sections 15.207 and 15.225

Passed

Straubing, May 18, 2018



Andreas Menacher  
Test engineer  
EMV **TESTHAUS** GmbH



Konrad Graßl  
Head of EMC department  
EMV **TESTHAUS** GmbH



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### 3 Equipment under Test (EUT)

Product type: Keyboard with multiple card readers  
Model Name: NEPTUN chrom  
Applicant: DESKO GmbH  
Manufacturer: DESKO GmbH  
Serial number: Prototype NEPTUN chrom  
FCC ID: WTM-NEPTUN1  
Application frequency band: 13.110 to 14.010 MHz  
Frequency range: 13.560 MHz  
Operating frequency: 13.560 MHz  
Number of RF-channels: 1  
Modulation: ASK  
Antenna connector:  permanent  temporary  none  
Antenna types: PCB antenna  
 detachable  not detachable  
Maximum antenna gain: N/A  
Maximum conducted power: N/A  
Power supply: 5.0 VDC  $\pm$  5 %  
Temperature range: 0°C to +50°C



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### 3.1 Photo documentation

For external photos of the EUT see annex B, for internal ones see annex C.  
For photos taken during testing and including EUT-positions see annex A.

### 3.2 Short description of the EUT

EUT is a keyboard with internal RFID reader (13.56 MHz).

### 3.3 Operation mode

During the pre-tests it was observed that the “continuous-tag reading-mode” is the respective worst- case. Therefore this mode was selected for final testing. The device was configured by manufacturer to scan the RFID-Tag and send the data to the Test-PC.

The EUT was only tested in 3 orthogonal positions for the measurements from 9 kHz to 30 MHz. The normal position (position 1) of the EUT was used for all other measurements. This is documented in annex A.



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### 3.4 Configuration

The following peripheral devices and interface cables were connected during the tests:

Device	Model:	Serial or inventory no.
Keyboard with multiple card readers	NEPTUN chrom	Prototype NEPTUN chrom
Power Supply	GT-46200-2005-T3	TR9CA4000YL4-N(R6B)
RFID tag	13.56 MHz	----
Notebook	LIFEBOOK U772	DSDA005103
DC supply	Statron 3231.1	E00017

### 3.5 Used cables

Count	Description (type / lengths / remarks)	Serial no.
1	USB cable (2.2 m, shielded)	---



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# 4 AC power line conducted emissions

according to 47 CFR Part 15, section 15.207

## 4.1 Test location

Description	Manufacturer	Inventory No.
Shielded room	Siemens - Matsushita	E00107

## 4.2 Test instruments

	Description	Manufacturer	Inventory No.
<input checked="" type="checkbox"/>	ESCS 30	Rohde & Schwarz	E00003
<input type="checkbox"/>	ESU 26	Rohde & Schwarz	W00002
<input type="checkbox"/>	ESCI	Rohde & Schwarz	E00001
<input type="checkbox"/>	ESH3-Z2	Rohde & Schwarz	E00028
<input checked="" type="checkbox"/>	ESH2-Z5	Rohde & Schwarz	E00004
<input type="checkbox"/>	ESH2-Z5	Rohde & Schwarz	E00005
<input checked="" type="checkbox"/>	Cable set shielded room	Huber + Suhner	E00424

## 4.3 Limits

Frequency [MHz]	Quasi-peak [dB $\mu$ V]	Average [dB $\mu$ V]
0.15 – 0.5	66 – 56	56 – 46
0.5 – 5.0	56	46
5 – 30	60	50



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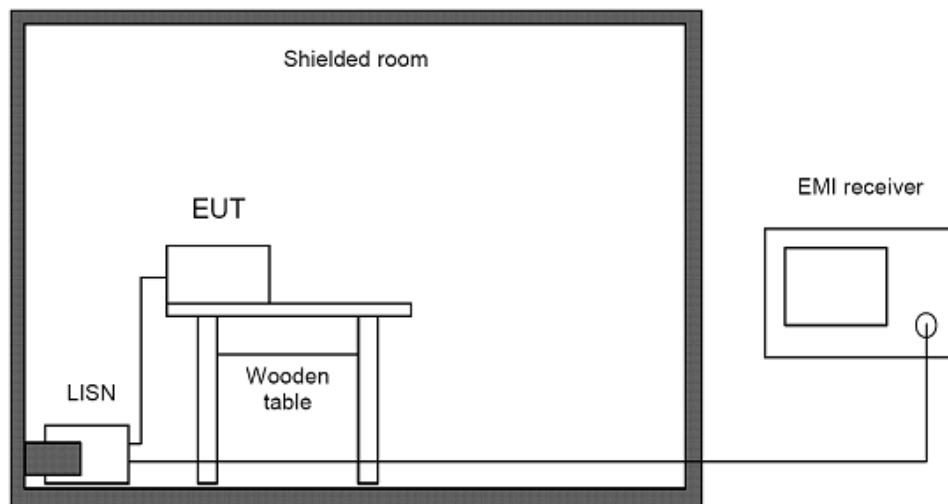
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## 4.4 Test procedure

1. The tests of conducted emission were carried out in a shielded room using a line impedance stabilization network (LISN) 50  $\mu$ H/50 Ohms and an EMI test receiver.
2. The EMI test receiver was connected to the LISN and set to a measurement bandwidth of 9 kHz in the frequency range from 0.15 MHz to 30 MHz.
3. The EUT was placed on a wooden table and connected to the LISN.
4. To accelerate the measurement the detector of the EMI test receiver was set to peak and the whole frequency range from 0.15 MHz to 30 MHz was scanned.
5. After that all peaks values with less margin than 10 dB to quasi-peak limit or exceeding the limit were marked and re-measured with quasi-peak detector.
6. If after that all values are under the average limit no addition measurement is necessary. In case there are still values between quasi-peak and average limit then these values were re-measured with average detector.
7. These measurements were done on all power lines.

According to ANSI C63.10, section 6.2.2 testing of intentional radiators with detachable antennas shall be done with a dummy load otherwise the tests should be done with connected antenna and if adjustable fully extended.

## 4.5 Test setup

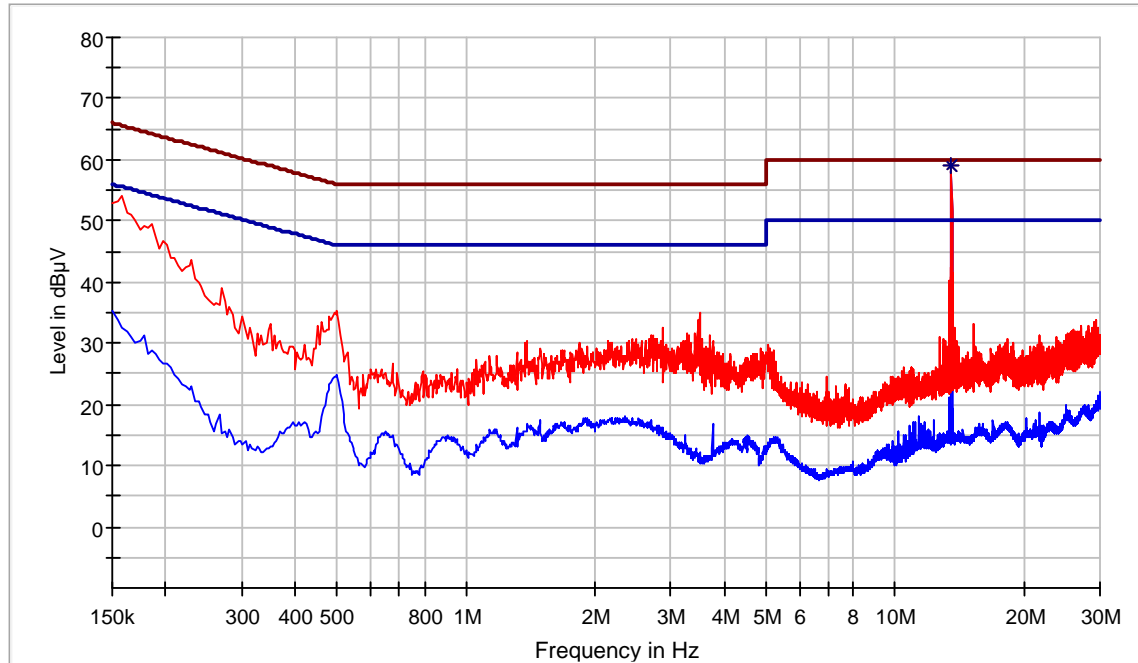


Picture 1: Outline of conducted emission test setup

Comments: All peripheral devices were additionally decoupled by means of a line stabilization network.

## 4.6 Test results

Temperature:	22°C	Humidity:	38%
Tested by:	Andreas Menacher	Test date:	2018-05-02



— Preview Result 2-AVG  
— Preview Result 1-PK+  
\* Final\_Result QPK  
\* Final\_Result AVG  
— 47 CFR §15.207 Conducted emission QP  
— 47 CFR §15.207 Conducted emission AV

Picture 2: Graphic - Conducted emission on mains, phase 1 (without termination)

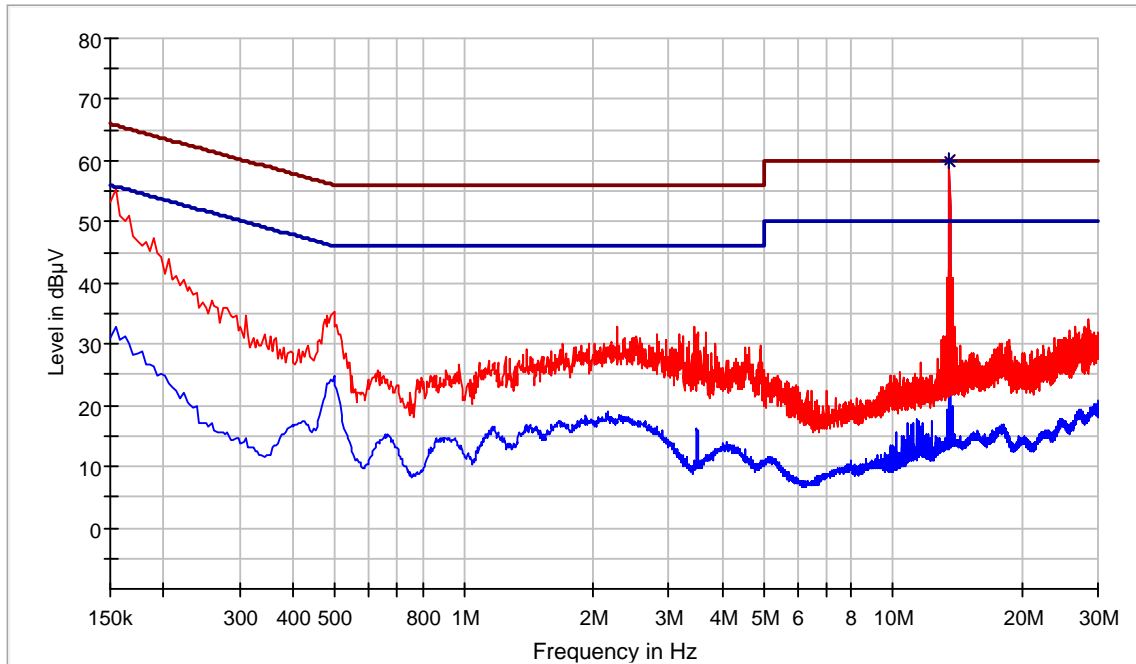
Frequency (MHz)	QuasiPeak (dBµV)	Average (dBµV)	Limit (dBµV)	Margin (dB)	Line	PE
13.561000	---	59.08	50.00	-9.08	L1	GND
13.561000	58.92	---	60.00	1.08	L1	GND

Picture 3: Table - Conducted emission on mains, phase 1 (without termination)



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— Preview Result 2-AVG  
— Preview Result 1-PK+  
— 47 CFR §15.207 Conducted emission AV  
— 47 CFR §15.207 Conducted emission QP  
\* Final\_Result QPK  
\* Final\_Result AVG

Picture 4: Graphic - Conducted emission on mains, neutral (without termination)

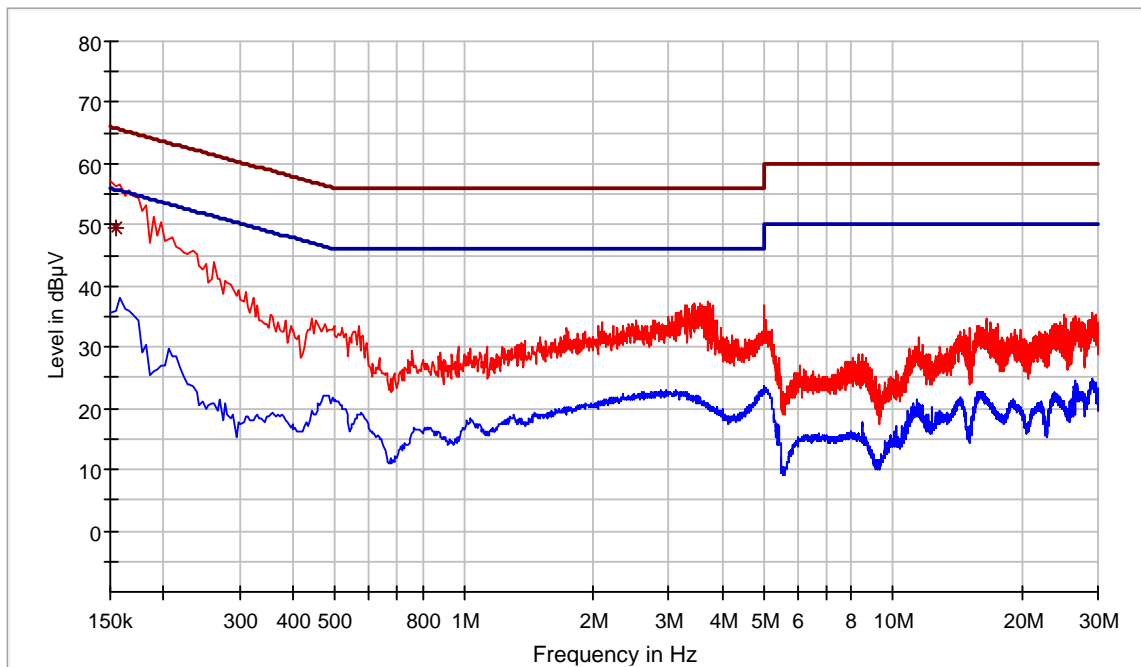
Frequency (MHz)	QuasiPeak (dBµV)	Average (dBµV)	Limit (dBµV)	Margin (dB)	Line	PE
13.561000	---	59.92	50.00	-9.92	N	GND
13.561000	59.89	---	60.00	0.11	N	GND

Picture 5: Table - Conducted emission on mains, neutral (without termination)



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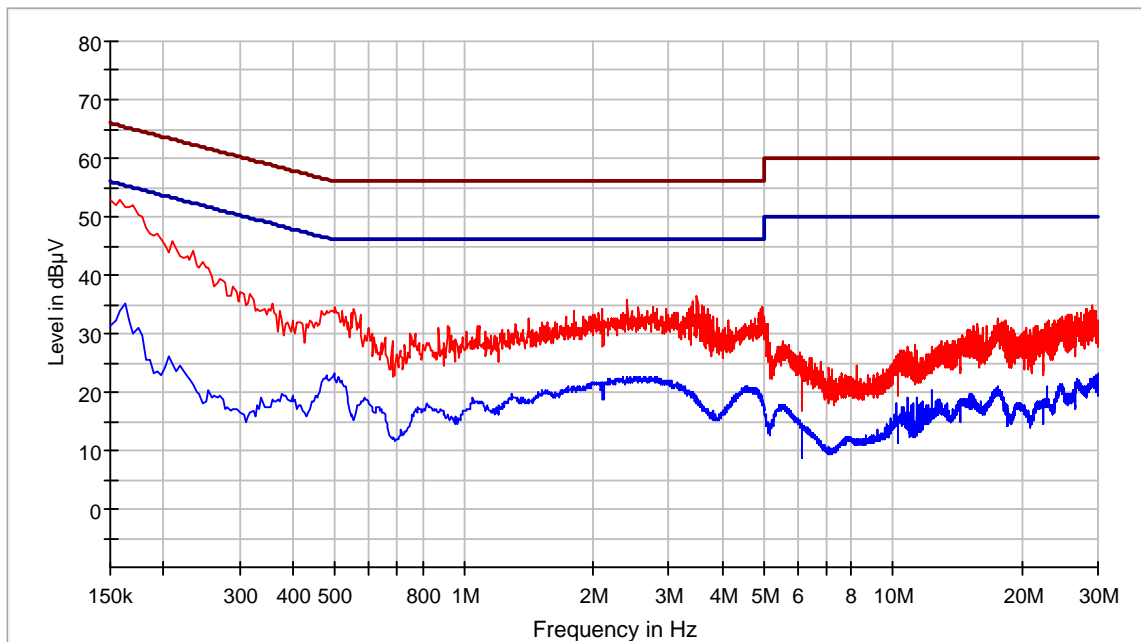


— Preview Result 2-AVG  
— Preview Result 1-PK+  
— 47 CFR §15.207 Conducted emission QP  
— 47 CFR §15.207 Conducted emission AV  
\* Final\_Result QPK  
\* Final\_Result AVG

Picture 6: Graphic - Conducted emission on mains, phase L1 (with termination)

Frequency (MHz)	QuasiPeak (dBµV)	Average (dBµV)	Limit (dBµV)	Margin (dB)	Line	PE
0.154000	49.61	---	65.78	16.17	L1	GND

Picture 7: Table - Conducted emission on mains, phase L1 (with termination)



- |   |                                      |   |                                      |
|---|--------------------------------------|---|--------------------------------------|
| — | Preview Result 2-AVG                 | — | Preview Result 1-PK+                 |
| * | Critical_Freqs AVG                   | * | Critical_Freqs PK+                   |
| — | 47 CFR §15.207 Conducted emission QP | — | 47 CFR §15.207 Conducted emission AV |
| * | Final_Result QPK                     | * | Final_Result AVG                     |

Picture 8: Graphic - Conducted emission on mains, neutral (with termination)



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# 5 Radiated emission measurement (<1 GHz)

according to 47 CFR Part 15, section 15.205(a), 15.209(a), 15.225(a) to (e)

## 5.1 Test Location

### Emission < 30 MHz

- Scan with PK / AV detector in 3 m CDC.
- Final CISPR measurement with QP detector in 3 m OATS

### Emission > 30 MHz

- Scan with QP detector in 3 m SAC.
- Final CISPR measurement with QP detector in 3 m SAC

## 5.2 Test instruments

Type	Designation	Manufacturer	Inventory no.
<input checked="" type="checkbox"/> Compact Diagnostic Chamber (CDC)	VK041.0174	Albatross Projects	E00026
<input checked="" type="checkbox"/> Semi Anechoic Chamber (SAC)	---	Albatross Projects	E00716
<input checked="" type="checkbox"/> Open area test site	---	EMV <b>TESTHAUS</b> GmbH	E00354
<input checked="" type="checkbox"/> EMI test receiver (CDC / OATS)	ESCI 3	Rohde & Schwarz	E00552
<input type="checkbox"/> EMI test receiver (SAC)	ESR 7	Rohde & Schwarz	E00739
<input checked="" type="checkbox"/> EMI test receiver	ESW 44	Rohde & Schwarz	E00895
<input type="checkbox"/> TRILOG broadband antenna (CDC)	VULB 9160	Schwarzbeck	E00011
<input type="checkbox"/> TRILOG broadband antenna (OATS)	VULB 9163	Schwarzbeck	E00013
<input checked="" type="checkbox"/> TRILOG broadband antenna (SAC)	VULB 9162	Schwarzbeck	E00643
<input checked="" type="checkbox"/> Loop Antenna	HFH2-Z2	Rohde & Schwarz	E00060
<input type="checkbox"/> Switch box	COSB 4-1-26	Conformitas	W00091
<input type="checkbox"/> Preamplifier	AMF-5D-00501800	Parzich	W00089
<input type="checkbox"/> Measurement software	E10 v1.4.12	EMV TESTHAUS GmbH	E00443
<input checked="" type="checkbox"/> Measurement software	EMC 32	Rohde & Schwarz	---
<input checked="" type="checkbox"/> Cable set SAC 3 m	---	Huber + Suhner	E00434 E00755 E00320



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## 5.3 Limits

The field strength of any emissions appearing outside of the 13.110 to 14.010 MHz band including spurious emissions falling into restricted bands as specified in 15.205(a) shall not exceed the general radiated emission limits as specified in 15.209.

Frequency [MHz]	Field strength Fs [ $\mu\text{V/m}$ ]	Field strength [dB $\mu\text{V/m}$ ]	Measurement distance d [m]
0.009 – 0.490	266.6 – 4.9	48.5 – 13.8	300
0.490 – 1.705	48.98 – 14.08	33.8 – 22.97	30
1.705 – 30.0	30	29.54	30
30 – 88	100	40	3
88 – 216	150	43.5	3
216 - 960	200	46	3
Above 960	500	54	3

As noted in 15.205(d)(7) devices according to 15.225 are exempt from complying with restricted band requirements for the 13.36 to 13.41 MHz band. Instead they have to comply with the limits as specified in 15.225 (a) to (d):

Frequency [MHz]	Field strength Fs [ $\mu\text{V/m}$ ]	Field strength [dB $\mu\text{V/m}$ ]	Measurement distance d [m]
13.553 - 13.567	15,848	84	30
13.410 - 13.553	334	50.47	30
13.567 - 13.710	334	50.47	30
13.110 - 13.410	106	40.51	30
13.710 - 14.010	106	40.51	30
f < 13.110	according to limits in §15.209		
f > 14.010			



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## 5.4 Test procedure

### Radiated emissions below 30 MHz

1. For emissions below 30 MHz measurements are done using a loop antenna. Prescan is performed with peak detector and final measurements with quasi-peak except for the frequency bands 9 to 90 kHz and 110 to 490 kHz where average detector applies. Antenna height is not changed during this test. Appropriate CISPR bandwidths of 200 Hz for frequencies up to 150 kHz and 9 or 10 kHz for frequencies above are used.
2. EUT is configured according to ANSI C63.10. It is placed on the top of the turntable 0.8 meter above ground. The receiving antenna is placed 3 meters from the turntable. The test setup is placed inside a fully anechoic room (called "CDC").
3. Then the EUT is rotated in a horizontal plane through 360° in steps of 45°. Starting at 0°, at each table position the spectrum for the full frequency range is recorded. If the emission at a certain frequency is higher than the levels already recorded, the current table position is noted as the maximum position
4. After the last prescan, the significant maximum emissions and their table positions are determined and collected in a list.
5. With the test receiver set to the first frequency of the list, the EUT is rotated by  $\pm 45^\circ$  around the table position found during prescans while measuring the emission level continuously. For final scan, the worst-case table position is set and the maximum emission level is recorded.
6. Step 5 is repeated for all other frequencies in the list.
7. Finally, for frequencies with critical emissions the loop antenna is rotated again to find the maximum of emission.

### Radiated emissions from 30 MHz to 1 GHz

1. EUT is configured according to ANSI C63.10. It was placed on the top of the turntable 0.8 meter above ground. The receiving antenna is placed 3 meters from the turntable. The test setup was placed inside a semi-anechoic chamber (SAC).
2. EUT and all peripherals are powered on.
3. The broadband antenna is set to vertical polarization.
4. The table position is set to 0°.
5. The antenna height is set to 1 m.
6. The spectrum for the full frequency range is recorded. If the emission at a certain frequency is higher than the levels already recorded, the polarization and height of the measurement antenna as well as the current table position are noted as the maximum position.
7. The antenna height is increased to 4 m in steps of 50 cm. At each height, step 6 is repeated.
8. The polarization of the measurement antenna is changed to horizontal.
9. The antenna height is decreased from 4 m to 1 m in steps of 50 cm. At each height, step 6 is repeated.
10. The EUT is rotated in a horizontal plane through 360° in steps of 60°. At each table position, steps 5 to 9 are repeated.
11. After the last prescan, the significant maximum emissions with their polarizations and heights of the measurement antenna as well as their table positions are determined and collected in a list.



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12. With the test receiver set to the first frequency of the list, the measurement antenna is set to the polarization and height and the table is moved to the position as determined during prescans.
13. The antenna is moved by  $\pm 50$  cm around this height and the EUT is rotated by  $\pm 60^\circ$  around this table position while measuring the emission level continuously.
14. For final scan, the worst-case positions of antenna and table are set and the maximum emission level is recorded.
15. Steps 12 to 14 are repeated for all other frequencies in the list.

If the EUT may be used in various positions, steps 1 to 15 are repeated in two other orthogonal positions.



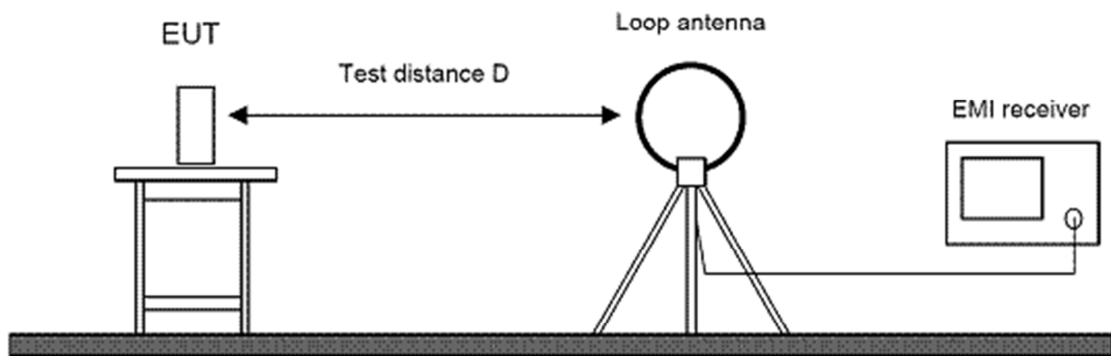
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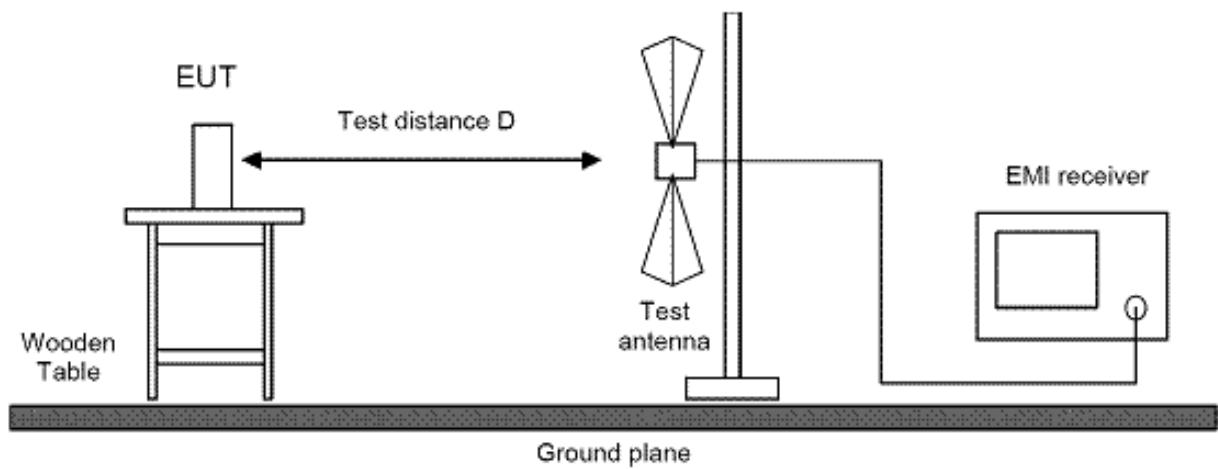
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## 5.5 Test setup



Picture 9: Test setup for radiated emission measurement (< 30 MHz)



Picture 10: Test setup for radiated emission measurement (< 1 GHz)

## 5.6 Test deviation

There is no deviation from the standards referred to.

## 5.7 Test results

Temperature:	21°C	Humidity:	37%
Tested by:	Andreas Menacher	Test date:	2018-05-03

### Radiated Emission Measurement 9 kHz - 30 MHz

Recalculation factor is determined according to ANSI C63.10, section 6.4.4.2 "Extrapolation from the measurement of a single point":

$$d_{\text{near field}} = 47.77 / f_{\text{MHz}}, \text{ or}$$

$$f_{\text{MHz}} = 47.77 / d_{\text{near field}}$$

The frequency  $f_{\text{MHz}}$  at which the near field distance is equal to the limit and/or test distance is important for selection of the right formula for determining the recalculation factor:

$$f_{\text{MHz}}(300 \text{ m}) \approx 0.159 \text{ MHz}$$

$$f_{\text{MHz}}(30 \text{ m}) \approx 1.592 \text{ MHz}$$

$$f_{\text{MHz}}(3 \text{ m}) \approx 15.923 \text{ MHz}$$

For  $9 \text{ kHz} \leq f \leq 159 \text{ kHz}$  and  $490 \text{ kHz} < f \leq 1.592 \text{ MHz}$ :

$$\text{Recalculation factor} = -40 \log(d_{\text{limit}} / d_{\text{measure}})$$

For  $159 \text{ kHz} < f \leq 490 \text{ kHz}$  and  $1.592 \text{ MHz} < f \leq 15.923 \text{ MHz}$ :

$$\text{Recalculation factor} = -40 \log(d_{\text{near field}} / d_{\text{measure}}) - 20 \log(d_{\text{limit}} / d_{\text{near field}})$$

For  $f > 15.923 \text{ MHz}$ :

$$\text{Recalculation factor} = -20 \log(d_{\text{limit}} / d_{\text{measure}})$$

The limits in the graphics and value lists are derived from the general radiated emission limits as specified in 15.209 using the recalculation factor as described above.



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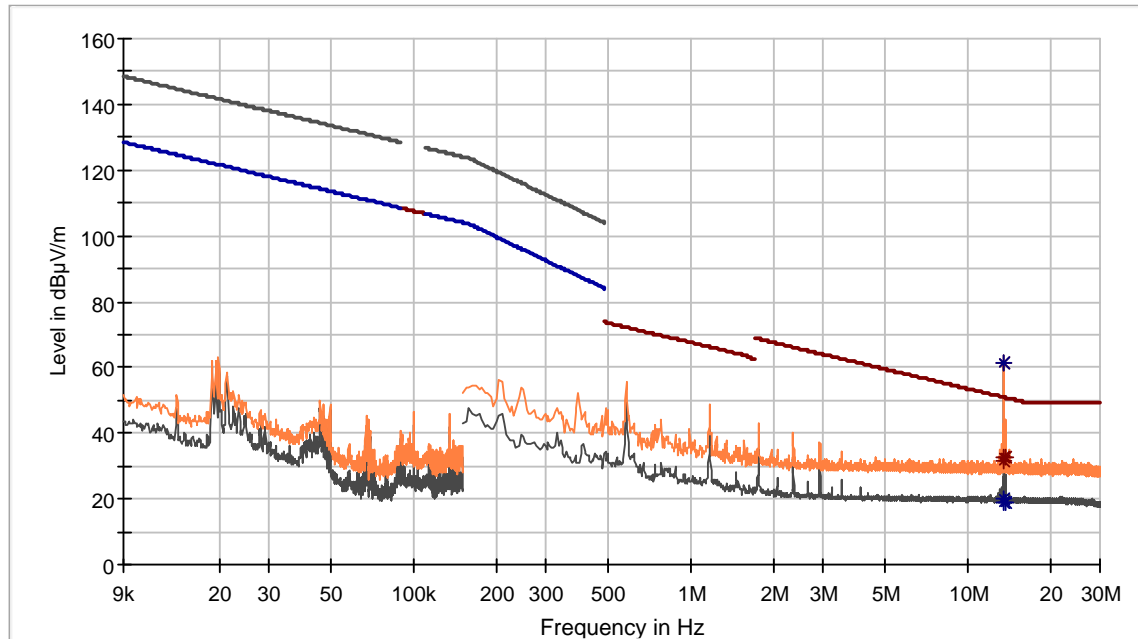
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Frequency range	Step size	IF Bandwidth	Detector		Measurement Time		Preamplifier
			Prescan	Final scan	Prescan	Final scan	
9 kHz – 90 kHz	80 Hz	200 Hz	PK	AV	1 ms	1 s	off
90 kHz – 110 kHz	80 Hz	200 Hz	PK	QPK	1 ms	1 s	off
110 kHz – 150 kHz	80 Hz	200 Hz	PK	AV	1 ms	1 s	off
150 kHz – 490 kHz	4 kHz	9 kHz	PK	AV	1 ms	1 s	off
490 kHz – 30 MHz	4 kHz	9 kHz	PK	QPK	1 ms	1 s	off

The following picture shows the worst-case-emissions for the spurious emissions at EUT-position 2, loop antenna parallel.



— Preview Result 2V-AVG  
 — 47 CFR §15.209 Radiated emission 3m QP  
 — 47 CFR §15.209 Radiated emission 3m PK  
 \* Final\_Result AVG  
 — Preview Result 1V-PK+  
 — 47 CFR §15.209 Radiated emission 3m AV  
 \* Final\_Result QPK

Frequency [MHz]	Measured value [dBµV/m]	Detector	Recalculation factor [dB]	Field strength [dBµV/m]	Limit [dBµV/m]	Margin	Result
13.447	20.08	AV	-21.46	-1.38	---	---	Carrier
13.447	31.38	QP	-21.46	9.92	50.47	40.55	Carrier
13.483	19.02	AV	-21.44	-2.42	---	---	Carrier
13.483	32.52	QP	-21.44	11.08	50.47	39.39	Carrier
13.560	61.27	AV	-21.40	39.87	---	---	Carrier
13.560	61.55	QP	-21.40	40.15	84.00	43.85	Carrier
13.659	18.98	AV	-21.33	-2.35	---	---	Carrier
13.659	32.88	QP	-21.33	11.55	50.47	38.92	Carrier

Picture 11: Radiated emission 9 kHz – 30 MHz @ 3m distance



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Recalculation factor is determined according to ANSI C63.10, section 6.4.4.2 “Extrapolation from the measurement of a single point”:

$$d_{\text{near field}} = 47.77 / f_{\text{MHz}}$$

$$\text{Recalculation factor} = -40 \log(d_{\text{near field}} / d_{\text{measure}}) - 20 \log(d_{\text{limit}} / d_{\text{near field}})$$

<b>f<sub>MHz</sub></b> <b>[MHz]</b>	<b>d<sub>near field</sub></b> <b>[m]</b>	<b>d<sub>measure</sub></b> <b>[m]</b>	<b>d<sub>limit</sub></b> <b>[m]</b>	<b>Recalculation factor [dB]</b>
13.447	3.552	3.0	30.0	-21.46
13.483	3.542	3.0	30.0	-21.44
13.560	3.552	3.0	30.0	-21.40
13.659	3.497	3.0	30.0	-21.33



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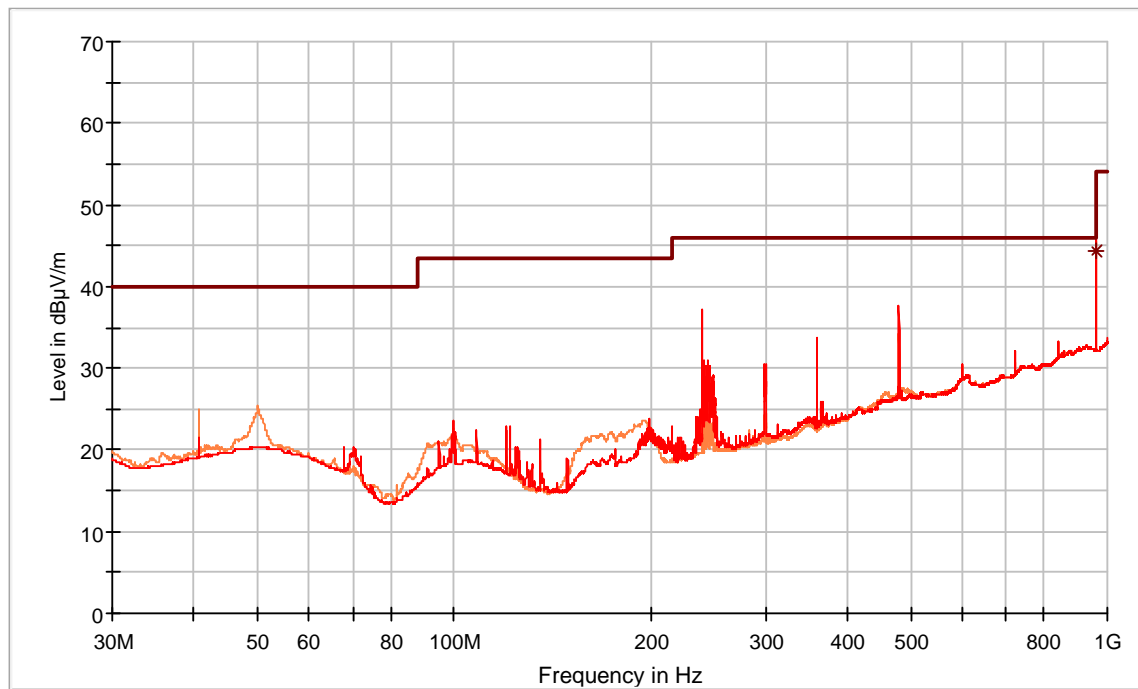
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# Radiated Emission Measurement 30 MHz - 1000 MHz

Frequency range	Polarisation	Step size	IF Bandwidth	Detector		Measurement Time		Pre-amplifier
				Prescan	Final scan	Prescan	Final scan	
30 MHz – 1 GHz	H / V	50 kHz	120 kHz	PK	QPK	1 ms	1 s	20 dB

The following pictures show the worst-case-emissions for EUT at normal position.



— Preview Result 1V-QPK  
— 47 CFR §15.109 Radiated emission 3m Class B QP  
\* Preview Result 1H-QPK  
\* Final\_Result QPK

Frequency (MHz)	QuasiPeak (dBµV/m)	Limit (dBµV/m)	Margin (dB)	Height (cm)	Pol	Azimuth (deg)
959.970000	44.45	46.00	1.55	100.0	H	264.0

Picture 12: Radiated emission 30 MHz - 1000MHz @ 3m distance



# Spectrum Mask

## Test procedure

The EUT was placed in a fully anechoic chamber and the testing was performed in accordance with ANSI C63.10 and 47 CFR Part 15, section 15.225 (a) to (d). The measurement distance was 3 m. To find the closest margin of the spectrum to the limit mask adapted to the test distance the EUT was rotated by 360 degrees with detector of the test receiver set to peak. The loop antenna placed in a fixed height of 1 meter was rotated by 360 degrees to get the maximum of emission. In case of exceeding the limits the detector is switched to quasi peak for final testing in position of maximum emission.

## Test result

Temperature:	21°C	Humidity:	37%
Tested by:	Andreas Menacher	Test date:	2018-05-03

Recalculation factor is determined according to ANSI C63.10, section 6.4.4.2 "Extrapolation from the measurement of a single point":

$$d_{\text{near field}} = 47.77 / f_{\text{MHz}}, \text{ or}$$

$$f_{\text{MHz}} = 47.77 / d_{\text{near field}}$$

The frequency  $f_{\text{MHz}}$  at which the near field distance is equal to the limit and/or test distance is important for selection of the right formula for determining the recalculation factor:

$$f_{\text{MHz}}(300 \text{ m}) \approx 0.159 \text{ MHz}$$

$$f_{\text{MHz}}(30 \text{ m}) \approx 1.592 \text{ MHz}$$

$$f_{\text{MHz}}(3 \text{ m}) \approx 15.923 \text{ MHz}$$

For  $9 \text{ kHz} \leq f \leq 159 \text{ kHz}$  and  $490 \text{ kHz} < f \leq 1.592 \text{ MHz}$ :

$$\text{Recalculation factor} = -40 \log(d_{\text{limit}} / d_{\text{measure}})$$

For  $159 \text{ kHz} < f \leq 490 \text{ kHz}$  and  $1.592 \text{ MHz} < f \leq 15.923 \text{ MHz}$ :

$$\text{Recalculation factor} = -40 \log(d_{\text{near field}} / d_{\text{measure}}) - 20 \log(d_{\text{limit}} / d_{\text{near field}})$$

For  $f > 15.923 \text{ MHz}$ :

$$\text{Recalculation factor} = -20 \log(d_{\text{limit}} / d_{\text{measure}})$$

The limits in the graphics and value lists are derived from the general radiated emission limits as specified in 15.209 using the recalculation factor as described above.



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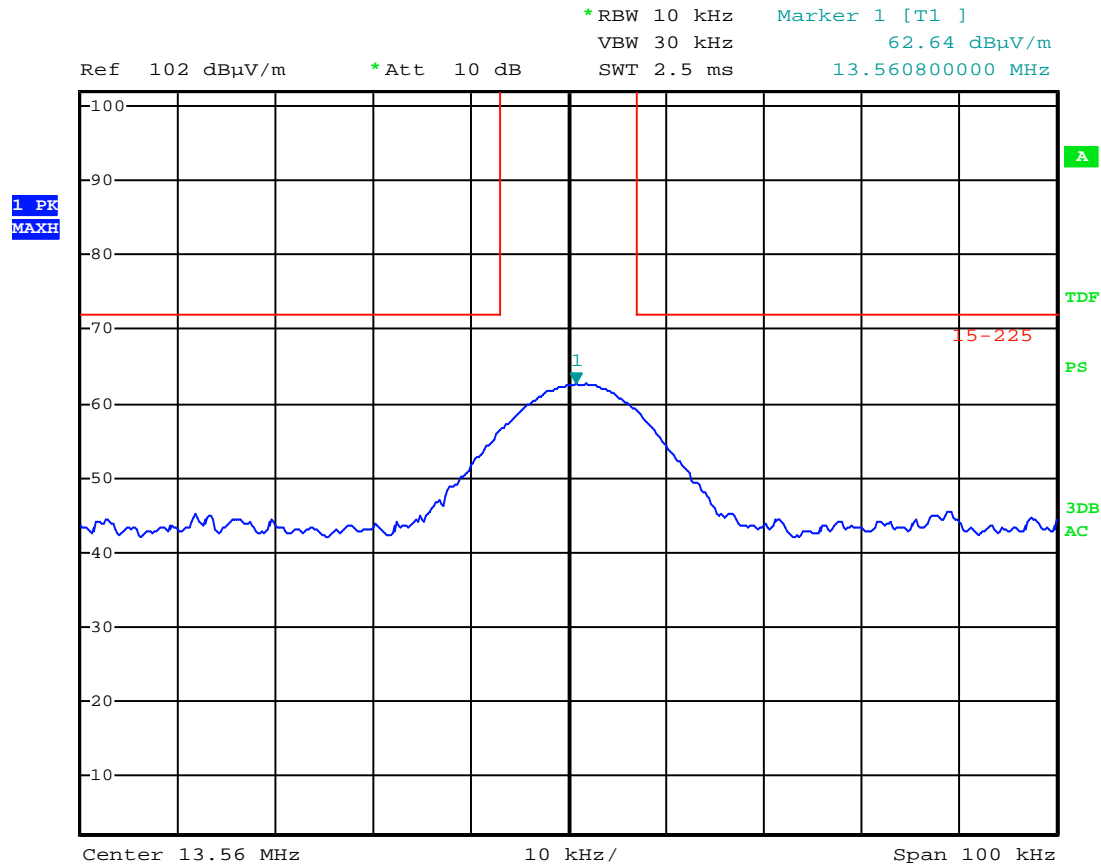
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Frequency range	Step size	IF Bandwidth	Detector		Measurement Time		Preamplifier
			Prescan	Final scan	Prescan	Final scan	
490 kHz – 30 MHz	4 kHz	9 kHz	PK	QPK	1 ms	1 s	off

The following pictures show the worst-case-emissions for spectrum mask at EUT-position 2, loop antenna parallel.



Picture 13: Spectrum mask for 13.56 MHz @ 3m distance

Frequency [MHz]	Measured value [dBμV/m]	Detector	Recalculation factor [dB]	Field strength [dBμV/m]	Limit [dBμV/m]	Margin [dB]	BW [kHz]
13.560	62.64	PK	-21.40	41.24	84.00	42.76	10



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Recalculation factor is determined according to ANSI C63.10, section 6.4.4.2 “Extrapolation from the measurement of a single point”:

$$d_{\text{near field}} = 47.77 / f_{\text{MHz}}$$

$$\text{Recalculation factor} = -40 \log(d_{\text{near field}} / d_{\text{measure}}) - 20 \log(d_{\text{limit}} / d_{\text{near field}})$$

$f_{\text{MHz}}$ [MHz]	$d_{\text{near field}}$ [m]	$d_{\text{measure}}$ [m]	$d_{\text{limit}}$ [m]	Recalculation factor [dB]
13.560	3.522	3.000	30.000	-21.40



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# 6 Radiated emission measurement (>1 GHz)

according to 47 CFR Part 15, section 15.209(a)

This measurement needs not to be applied for the RFID part because

- the intentional radiator operates below 10 GHz and tenth harmonic of the highest fundamental frequency is lower than 1 GHz (see 47 CFR Part 15, section 15.33(a)(1), and RSS-Gen, section 6.13).



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# 7 Carrier frequency stability

according to CFR 47 Part 15, section 15.225(e)

## 7.1 Test Location

	Description	Manufacturer	Inventory No.
<input type="checkbox"/>	Climatic chamber VC 4100	Vötsch Industrietechnik	C00014
<input checked="" type="checkbox"/>	Climatic chamber VC <sup>3</sup> 4034	Vötsch Industrietechnik	C00015

## 7.2 Test instruments

	Description	Manufacturer	Inventory No.
<input type="checkbox"/>	ESU 26	Rohde & Schwarz	W00002
<input checked="" type="checkbox"/>	ESCI	Rohde & Schwarz	E00001
<input checked="" type="checkbox"/>	RF-R 400-1	Langer EMV-Technik	E00270

## 7.3 Limits

The frequency tolerance of the carrier signal shall be maintained within  $\pm 0.01\%$  (100 ppm) of the operating frequency over a temperature variation of -20 degrees to +50 degrees C at normal supply voltage, and for a variation in the primary supply voltage from 85% to 115% of the rated supply voltage at a temperature of 20 degrees C.

For battery operated equipment, the equipment tests shall be performed using a new battery. Alternatively, an external supply voltage can be used and set at the battery nominal voltage, and again at the battery operating end point voltage which must be specified by the equipment manufacturer.



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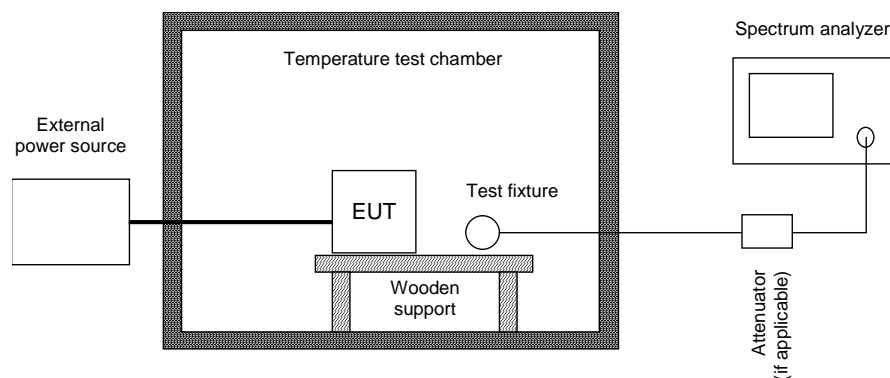
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## 7.4 Test procedure

1. If possible EUT is operating providing an unmodulated carrier. The peak detector of the spectrum analyzer is selected and resolution as well as video bandwidth are set to values appropriate to the shape of the spectrum of the EUT. The frequency counter mode of the spectrum analyzer is used to maximize the accuracy of the measured frequency tolerance.  
If an unmodulated carrier is not available a significant and stable point on the spectrum is selected and the span is reduced to a value that delivers an accuracy which shall be better than 1% of the maximum frequency tolerance allowed for the carrier signal. This method may be performed as long as the margin to the frequency tolerance allowed is larger than the uncertainty of the measured frequency tolerance.
2. The carrier frequency is measured depending on the variation in the primary supply voltage from 85% to 115% of the rated supply voltage at a temperature of 20 degrees C. For battery operated equipment an external supply voltage can be used and set at the battery nominal voltage, and again at the battery operating end point voltage which must be specified by the equipment manufacturer. Alternatively, tests shall be performed using a new battery.
3. The carrier frequency is measured over a temperature variation of -20 degrees to +50 degrees C at normal supply voltage.

## 7.5 Test setup



Picture 14: Test setup for carrier frequency stability measurement

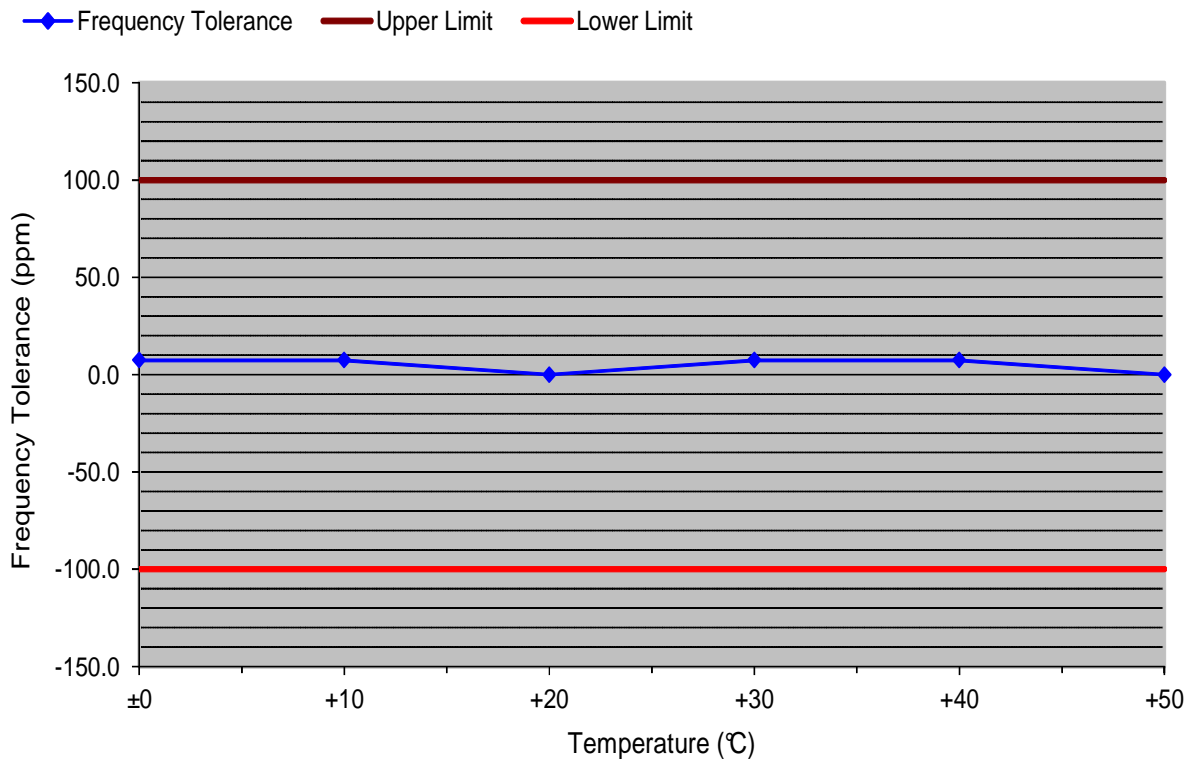
## 7.6 Test deviation

There is no deviation from the standards referred to.

## 7.7 Test result

Temperature:	21°C	Humidity:	37%
Tested by:	Andreas Menacher	Test date:	2018-05-03

### Carrier frequency stability vs. temperature



Supply voltage:	5 V	Frequency under nominal conditions:	13.561 MHz			
Temperature (°C)	Frequency (MHz)	Frequency Tolerance (Hz)	Frequency Tolerance (ppm)	Upper Limit (ppm)	Lower Limit (ppm)	Margin (ppm)
±0	13.561100	100	7.4	+100.0	-100.0	92.6
+10	13.561100	100	7.4	+100.0	-100.0	92.6
+20	13.561000	0	0.0	+100.0	-100.0	100.0
+30	13.561100	100	7.4	+100.0	-100.0	92.6
+40	13.561100	100	7.4	+100.0	-100.0	92.6
+50	13.561000	0	0.0	+100.0	-100.0	100.0



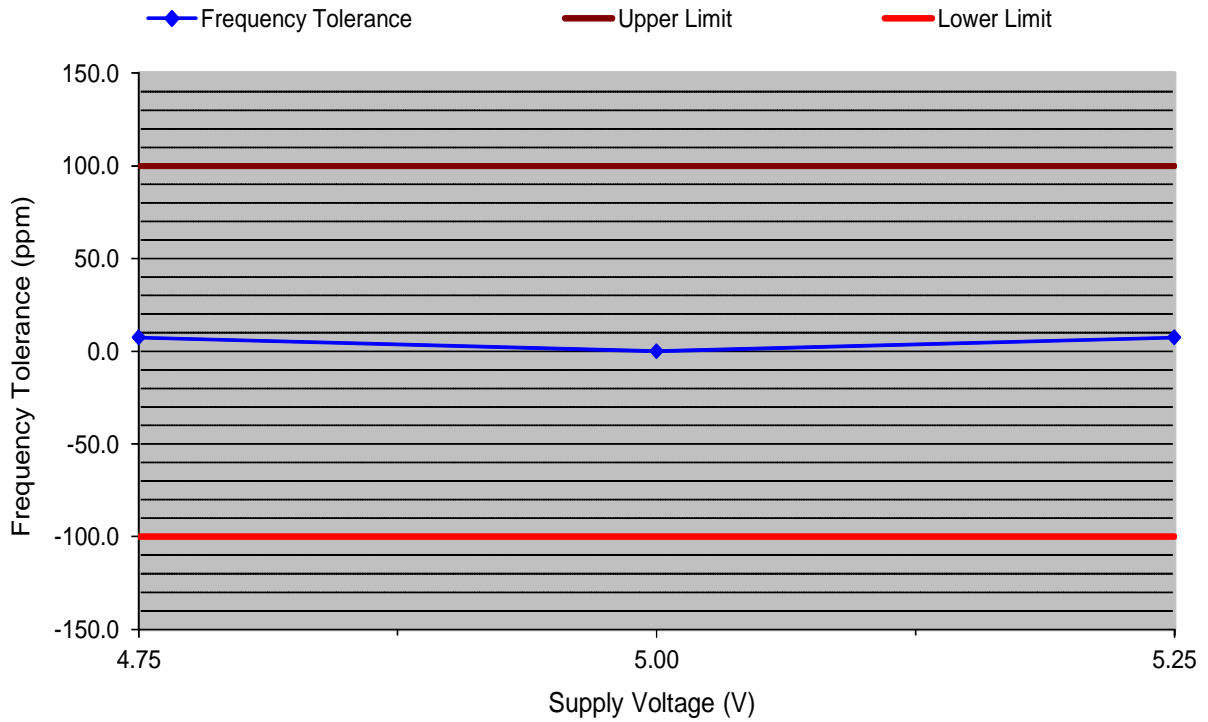
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## Carrier frequency stability vs. supply voltage



Temperature:	+20 °C	Battery End Point:	Not applicable			
Frequency under nominal conditions:	13.561 MHz					
Supply Voltage (V)	Frequency (MHz)	Frequency Tolerance (Hz)	ppm	Upper Limit (ppm)	Lower Limit (ppm)	Margin (ppm)
4.75	13.561100	100	7.4	+100.0	-100.0	92.6
5.00	13.561000	0	0.0	+100.0	-100.0	100.0
5.25	13.561100	100	7.4	+100.0	-100.0	92.6



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# 8 Bandwidths

according to CFR 47 Part 2, section 2.202(a)

## 8.1 Test Location

See clause 5.1 on page 16.

## 8.2 Test instruments

See clause 0 on page 16.

## 8.3 Limits

The bandwidths are recorded only. There are no limits specified in CFR 47 Part 15, section 15.225

## 8.4 Test setup

See clause 5.5 on page 20.

## 8.5 Test deviation

There is no deviation from the standards referred to.



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## 8.6 Test results

Temperature:	21°C	Humidity:	37%
Tested by:	Andreas Menacher	Test date:	2018-05-03

### Occupied bandwidth (99 %)

#### Test procedure

When an occupied bandwidth value is not specified in the applicable RSS, the transmitted signal bandwidth to be reported is to be its 99% emission bandwidth, as calculated or measured. The transmitter shall be operated at its maximum carrier power measured under normal test conditions.

The span of the analyzer shall be set to capture all products of the modulation process, including the emission skirts. The resolution bandwidth shall be set to as close to 1% of the selected span as is possible without being below 1%. The video bandwidth shall be set to 3 times the resolution bandwidth. Video averaging is not permitted. Where practical, a sampling detector shall be used given that a peak or peak hold may produce a wider bandwidth than actual.

The trace data points are recovered and directly summed in linear terms. The recovered amplitude data points, beginning at the lowest frequency, are placed in a running sum until 0.5% of the total is reached and that frequency recorded. The process is repeated for the highest frequency data points. This frequency is recorded. The span between the two recorded frequencies is the occupied bandwidth. For this purpose the appropriate measurement function of the spectrum analyzer is used.

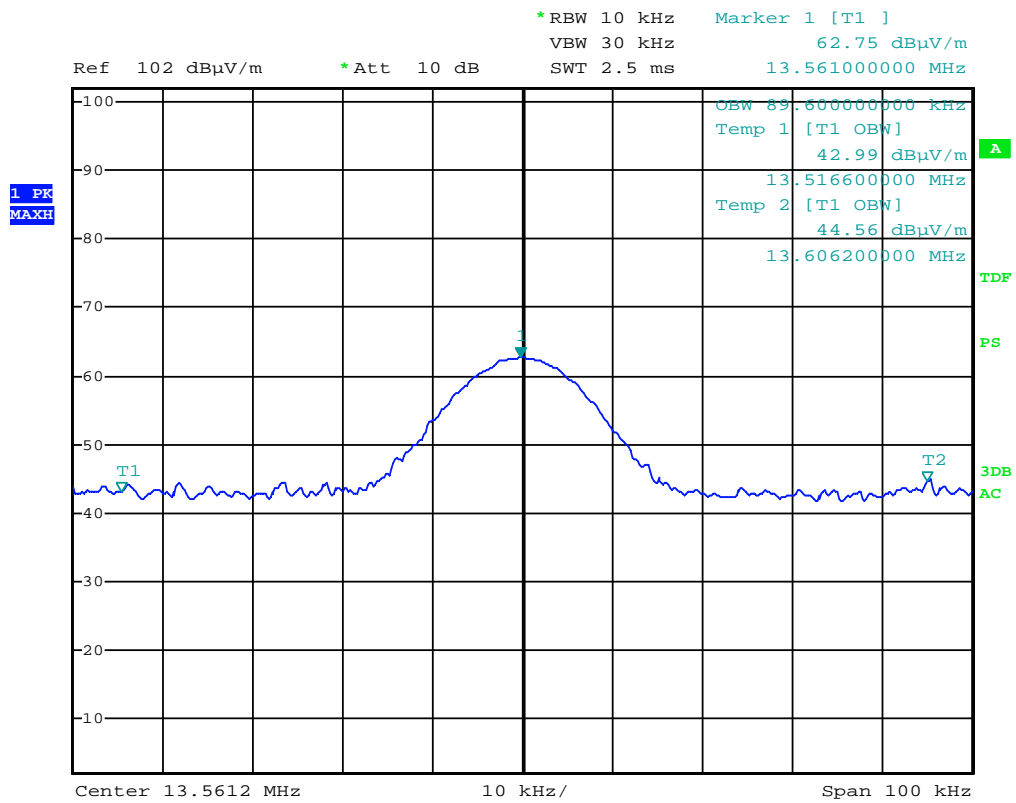


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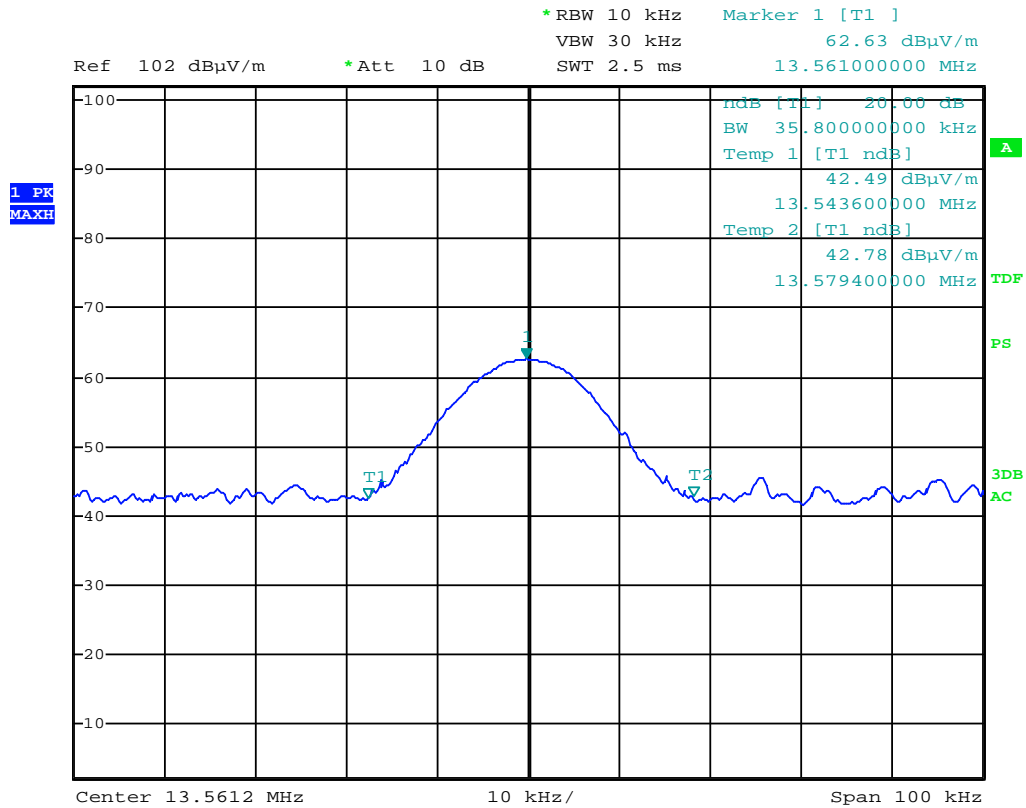
Picture 15: Occupied bandwidth (99 %)

Measured occupied bandwidth (99 %): 89.600 kHz

# -20 dB emission bandwidth

## Test procedure

Where indicated, the -20 dB emission bandwidth is defined as the frequency range between two points, one above and one below the carrier frequency, at which the spectral density of the emission is attenuated 20 dB below the maximum in-band spectral density of the modulated signal. Spectral density (power per unit bandwidth) is to be measured with a detector of resolution bandwidth equal to approximately 1.0% of the emission bandwidth.



Picture 16: -20 dB emission bandwidths

Measured -20 dB emission bandwidth: 35.800 kHz



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$f_{\text{assigned}}$ (MHz)	Index	$f_{-20\text{dB}}$ (MHz)	$\Delta f_T$ (kHz)	$\Delta f_U$ (kHz)	$f_{-20\text{dB}(T, U)}$ (MHz)	Limit (MHz)	Margin (kHz)	Result
13.56100	low	13,543600	0.000	0.000	13.543600	13.110000	433.600	Passed
	high	13,579400	0.100	0.100	13.579600	14.010000	430.400	Passed
	Bandwidth	35.800 kHz			36.000 kHz			

with:  $f_{-20\text{dB}(\text{low})}$  = lower frequency in MHz where emission is at least 20 dB below the carrier  
 $f_{-20\text{dB}(\text{high})}$  = upper frequency in MHz where emission is at least 20 dB below the carrier  
 $f_{\text{assigned}}$  = assigned frequency in kHz  
 $\Delta f_{T(\text{low})}$  = maximum absolute value of negative frequency offset to frequency at nominal conditions caused by temperature variation in kHz  
 $\Delta f_{U(\text{low})}$  = maximum absolute value of negative frequency offset to frequency at nominal conditions caused by voltage variation in kHz  
 $\Delta f_{T(\text{high})}$  = maximum absolute value of positive frequency offset to frequency at nominal conditions caused by temperature variation in kHz  
 $\Delta f_{U(\text{high})}$  = maximum absolute value of positive frequency offset to frequency at nominal conditions caused by voltage variation in kHz  
 $\Delta f_{\text{volt}(\text{high})}$  = maximum absolute value of positive frequency offset to frequency at nominal conditions caused by voltage variation in kHz  
 $f_{-20\text{dB}(T, U)}$  = frequency in MHz where emission is at least 20 dB below the carrier, including offset caused by variations of temperature and supply voltage as recorded in clause 7.7

Measured -20 dB emission bandwidth:

At nominal conditions: 35.800 kHz

Including variations in temperature and supply voltage: 36.000 kHz



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## 9 Equipment calibration status

Description	Modell number	Serial number	Inventory number(s)	Last calibration	Next calibration
Test receiver	ESCI 3	100328	E00552	2016-09	2018-09
Test receiver	ESCS 30	825442/0002	E00003	2016-04	2018-05 <sup>1</sup>
Test receiver	ESR 7	101059	E00739	2016-02	2019-02
LISN	ESH2-Z5	893406/009	E00005	2016-02	2019-02
Loop antenna	HFH2-Z2	871398/0050	E00060	2016-09	2018-09
Broadband antenna	VULB 9162	9160-3050	E00011	2018-03	2020-03
Shielded room	P92007	B83117C1109T211	E00107	N/A	
Compact diagnostic chamber (CDC)	VK041.0174	D62128-A502-A69-2-0006	E00026	N/A	
Cable set shielded room	Cable no. 30	---	E00424	2016-07	2018-07
Cable set CDC	Cables no. 37 and 38	---	E00459 E00460	2017-05	2019-05
Cable set OATS 3 m	Cables no. 19, 34 and 36	---	E00453 E00456 E00458	2015-11	2018-11
Cable set SAC 3 m	Cables no. 04, 52 and 12	---	E00434 E00755 E00320	2015-11	2018-11

Table 1: Equipment calibration status

Note 1: Expiration date of test firm accreditation for OATS and SAC:  
FCC test firm type "accredited": 2019-05

<sup>1</sup> Calibration valid until 2018-05-30.



# 10 Measurement uncertainty

Description	Max. deviation	k=
Conducted emission AMN (150 kHz to 30 MHz)	± 3.4 dB	2
Radiated emission open field (3 m) (9 kHz to 30 MHz) (30 MHz to 300 MHz) (300MHz to 1 GHz)	± 4.8 dB ± 5.4 dB ± 5.9 dB	2
Radiated emission absorber chamber (> 1000 MHz)	± 4.5 dB	2

Table 2: Measurement uncertainty

The uncertainty stated is the expanded uncertainty obtained by multiplying the standard uncertainty by the coverage factor k. For a confidence level of 95 % the coverage factor k is 2.



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# 11 Revision History

Date	Description	Person	Revision
2018-05-18	First edition	Andreas Menacher	0



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